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RESISTORS, FIXED, FILM

BASED ON TYPE CHP HR 1206

ESCC Detail Specification No. 4001/020

ISSUE 1 October 2002



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RESISTORS, FIXED, CHIPS, FILM

BASED ON TYPE CHP HR 1206

ESA/SCC Detail Specification No. 4001/020

space components coordination group

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DOCUMENTATION CHANGE NOTICE

Rev. Letter	Rev. Date	CHANGE Reference Item		
'A'	Jan. '01	P1. Cover page P2. DCN P6. Table 1(a) : No. 01, Minimum Resistance Range value amended : No. 02, Minimum Resistance Range value amended	None None 221601 221601	
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<u>APPENDICES</u> (Applicable to specific Manufacturers only) None.



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1. <u>GENERAL</u>

1.1 <u>SCOPE</u>

This specification details the ratings, physical and electrical characteristics, test and inspection data for Resistors, Fixed, Chips, Film, based on Type CHP HR 1206. It shall be read in conjunction with ESA/SCC Generic Specification No. 4001, the requirements of which are supplemented herein.

1.2 RANGE OF COMPONENTS

The range of resistors covered by this specification is given in Table 1(a).

1.3 MAXIMUM RATINGS

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the resistors specified herein, are as scheduled in Table 1(b).

1.4 PARAMETER DERATING INFORMATION

The parameter derating information applicable to the resistors specified herein is given in Figure 1.

1.5 PHYSICAL DIMENSIONS

The physical dimensions of the resistors specified herein, are shown in Figure 2.

1.6 FUNCTIONAL DIAGRAM

The functional diagram for the resistors specified herein, is shown in Figure 3.

2. <u>APPLICABLE DOCUMENTS</u>

The following documents form part of this specification and shall be read in conjunction with it:-

(a) ESA/SCC Generic Specification No. 4001, Resistors, Fixed, Film.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply. In addition, the following symbols are used:-

 V_T = Test Voltage.

TC = Temperature Coefficient.



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TABLE 1(a) - RANGE OF COMPONENTS

No.	Resistance Range (Note 1)		Tolerance	Value	Temperature Coefficient
	Min.	Max.	(±%)	Series	(±10 ^{−6/°} C)
01	10.2Ω	1.0MΩ	1.0	E96	100
02	10.5Ω	1.0MΩ	2.0	E48	100
03	1.0Ω	10Ω	1.0	E96	200
04	1.0Ω	10Ω	2.0	E48	200

NOTES

1. Critical resistance = 90 000 Ω .

2. For Variants, see Figure 2 and Para.. 4.4.2.

No.	Characteristics	Symbol	Limits	Unit	Remarks
1	Rated Dissipation	Pn	0.25	w	Note 1
2	Limiting Element Voltage	UL	150	V	-
3	Rated Voltage	U _R	√ (0.25 R _n)	V	Note 2
4	Insulation Voltage	Ui	200	Vrms	-
5	Operating Temperature Range	T _{op}	-55 to +155	°C	T _{amb}
6	Storage Temperature Range	T _{stg}	−55 to +155	°C	-
7	Soldering Temperature	T _{sol}	+ 260	°C	Note 3

TABLE 1(b) - MAXIMUM RATINGS

NOTES

1. At $T_{amb} \le +70^{\circ}$ C. For derating at $T_{amb} > +70^{\circ}$ C, see Figure 1.

2. Shall never exceed Limiting Element Voltage.

3. Duration 10 seconds maximum.

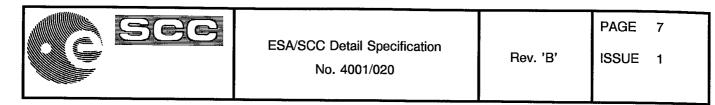
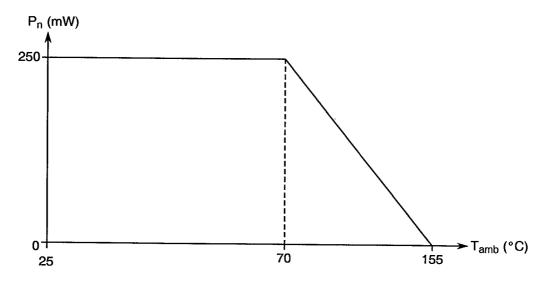


FIGURE 1 - PARAMETER DERATING INFORMATION

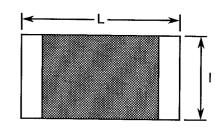


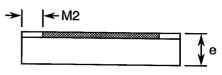
Rated Dissipation versus Temperature



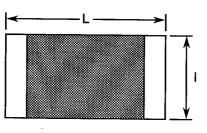
FIGURE 2(a) - VARIANTS 01 AND 03

FIGURE 2(b) - VARIANT 02





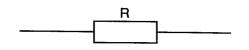
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SYMBOL	MILLIMETRES		
S TMBOL	MIN.	MAX.	
L	2.95	3.45	
I	1.45	1.75	
е	0.64	0.65	
M1	0.40	0.60	
M2	0.20	0.40	

FIGURE 3 - FUNCTIONAL DIAGRAM





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4. **REQUIREMENTS**

4.1 <u>GENERAL</u>

The complete requirements for procurement of the resistors specified herein shall be as stated in this specification and ESA/SCC Generic Specification No. 4001. Deviations from the Generic Specification, applicable to this specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

4.2 DEVIATIONS FROM GENERIC SPECIFICATION

- 4.2.1 <u>Deviations from Special In-process Controls</u> None.
- 4.2.2 Deviations from Final Production Tests (Chart II)
 - (a) Para. 9.1, Overload: Before Overload, the resistors shall be submitted to Para. 12, Rapid Change of Temperature.

The test conditions for Overload shall be:-

Voltage: $\sqrt{0.375}$ R_n or 150V, whichever is less. Duration: 24 hours minimum.

- (b) Para. 9.2, Third Harmonic Control or Current Noise: Not applicable.
- (c) Para. 9.5.3, Electrical Measurements at High and Low Temperatures: Shall be performed.
- 4.2.3 <u>Deviations from Burn-in and Electrical Measurements (Chart III)</u>
 - (a) Para. 9.5.3, Electrical Measurements at High and Low Temperatures: Shall not be performed.
- 4.2.4 Deviations from Qualification Tests (Chart IV)
 - (a) Para. 9.1, Overload: Test conditions as Para. 4.2.2(a) and in addition, Resistance Change measurements shall be performed as given in Table 6 of this specification.
 - (b) Para. 9.9, Solderability: Not applicable for Variant 02.
 - (c) Para. 9.10, Robustness of Terminations: Not applicable for Variant 02.
 - (d) Para. 9.11, Resistance to Soldering Heat: Not applicable for Variant 02.
 - (e) Para. 9.13, Vibration: Not applicable.

4.2.5 Deviations from Lot Acceptance Tests (Chart V)

- (a) Para. 9.9, Solderability: Not applicable for Variant 02.
- (b) Para. 9.10, Robustness of Terminations: Not applicable for Variant 02.
- (c) Para. 9.11, Resistance to Soldering Heat: Not applicable for Variant 02.
- (d) Para. 9.13, Vibration: Not applicable.



4.3 MECHANICAL REQUIREMENTS

4.3.1 Dimension Check

The dimensions of the resistors specified herein shall be verified in accordance with the requirements set out in Para. 9.4 of ESA/SCC Generic Specification No. 4001 and shall conform to those shown in Figure 2 of this specification.

4.3.2 Weight

The maximum weight of the resistors specified herein shall be 0.009 grammes.

4.3.3 Robustness of Terminations

The requirements and test conditions for robustness of terminations are specified in Para. 9.10.2 of ESA/SCC Generic Specification No. 4001.

4.4 MATERIALS AND FINISHES

The materials and finishes shall be as specified herein. Where a definite material is not specified, a material which will enable the components specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material does not guarantee acceptance of the finished product.

4.4.1 <u>Case</u>

The alumina substrate shall be covered with a suitable inorganic coating.

4.4.2 <u>Terminations</u>

Variant 01

The resistors shall be terminated with gold/platinum with a solder coating of 62Sn, 36Pb, 2.0Ag%.

Variant 02

The resistors shall be terminated with thick film gold.

Variant 03

The resistors shall be terminated with gold/platinum with a nickel barrier and a solder coating of 95Sn, 5.0Pb%.

4.4.3 <u>Films</u>

Thick films shall be uniformly deposited. They shall be free from blisters, thin spots, areas inadequately bonded to the core, discoloured spots or other blemishes likely to cause flaking. Trimming shall occupy at maximum 30% of the width of the resistance element.



4.5 MARKING

4.5.1 <u>General</u>

The marking of all components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700 and the following paragraphs. When the component is too small to accommodate all of the marking specified, the component shall be colour coded as specified in the above specification.

The marking information in full shall accompany each component in its primary package. Such marking shall comprise:-

- (a) Electrical Characteristics and Ratings.
- (b) The SCC Component Number.
- (c) Traceability Information.

4.5.2 <u>Electrical Characteristics and Ratings</u>

The electrical characteristics and ratings to be marked in the following order of precedence are:-

- (a) Resistance Value.
- (b) Tolerance.
- (c) Temperature Coefficient.

The information shall be constituted and marked as follows:

		2490F	4
Value (249 Ohms) -			T
Tolerance (±1.0%)			
Temperature Coefficie	ent (± 100 10 ^{-6/°} C)		_

4.5.2.1 Resistance Values

Resistance values shall be expressed by means of the following codes. The unit quantity for marking shall be Ohms (Ω).

Resistance Value	Code
XX.X	XXRX
XXX	XXX0
XXX101	XXX1
XXX10 ²	XXX2
XXX10 ³	XXX3
XXX104	XXX4

For values of 100Ω and above, the first 3 digits (X) represent significant figures and the last digit specifies the number of zeros to follow.

When values of less than 100Ω are required, the letter 'R' is used to indicate the decimal point. When the letter is used, all successive digits represent significant figures.



4.5.2.2 Tolerance

The tolerance on resistance values shall be indicated by the code letters specified hereafter.

Tolerance (±%)	Code Letter
1.0	F
2.0	G

4.5.2.3 Temperature Coefficient

The temperature coefficient shall be indicated by the numerical codes specified hereafter.

Temperature Coefficient (±10 ^{-6/°} C)
100
200

4.5.3 The SCC Component Number

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:

Detail Specification Number	400102001B
Type Variant (see Note)	
Testing Level (B or C, as applicable)	

<u>N.B.</u>

For Variants, see Para. 4.4.2.

4.5.4 Traceability Information

Each component shall be marked in respect of traceability information in accordance with the requirements of ESA/SCC Basic Specification No. 21700.

4.6 ELECTRICAL MEASUREMENTS

4.6.1 <u>Electrical Measurements at Room Temperature</u>

The parameters to be measured at room temperature are scheduled in Table 2. Unless otherwise specified, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.6.2 <u>Electrical Measurements at High and Low Temperatures</u>

The parameters to be measured on a sample basis at high and low temperatures are scheduled in Table 3.

The distribution of the sample shall be as follows:

- 1/3 with the lowest resistance value,
- 1/3 with the highest resistance value,
- 1/3 with the median resistance value or the critical resistance value if procured,
- of the procured range.



4.6.3 <u>Circuits for Electrical Measurements (Figure 4)</u>

Not applicable.

4.7 <u>BURN-IN TESTS</u>

4.7.1 Parameter Drift Values

The parameter drift values applicable to burn-in are specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at $T_{amb} = +22 \pm 3$ °C. The parameter drift values (Δ) applicable to the parameters scheduled, shall not be exceeded. In addition to these drift value requirements, the appropriate limit value specified in Table 2 for a given parameter shall not be exceeded.

4.7.2 <u>Conditions for Burn-in</u>

The requirements for burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 4001. The conditions for burn-in shall be as specified in Table 5 of this specification.

After 168(+24-0) hours, the resistors shall be removed from the chamber and allowed to cool under normal atmospheric conditions for a minimum of 4 hours. They shall then be visually examined. There shall be no evidence of damage and the marking shall still be legible.

4.7.3 Electrical Circuit for Burn-in

The circuit for use in performing the burn-in test is shown in Figure 5 of this specification.



TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE

No.	Characteristics	Symbol	ESA/SCC 4001	LSA/SUC 4001 Test		Lir	nits	Linit
		Cymbol	Test Method	Conditions	(±%)	Min.	Max.	Unit
1	Resistance	R _A	Para. 9.5.1	Para. 9.5.1	1.0	0.99 R _n	1.01 R ₀	Ω
					2.0	0.98 R _n	1.02 R _n	

TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES

No.	Characteristics	Symbol	ESA/SCC 4001	Test Conditions	Lin	Unit	
		Cymool	Test Method	(Note 1)	Min.	Max.	Unit
2	Resistance Change between -55(+3-0) °C and +22±3 °C	<u>ΔR</u> R	Para. 9.5.1	Para. 9.5.1 ± 100 10 ^{-6/°} C ± 200 10 ^{-6/°} C	- 0.77 - 1.54	+ 0.77 + 1.54	%
3	Resistance Change between +155(+0-3) °C and +22±3 °C	Δ <u>R</u> R	Para. 9.5.1	Para. 9.5.1 ± 100 10 ^{6/°} C ± 200 10 ^{6/°} C	- 1.33 - 2.66	+ 1.33 + 2.66	%

NOTES

1. The measurements shall be performed on a sample basis in accordance with Special Inspection Level S-3, Table IIA, AQL = 1.0% of IEC Publication No. 410 on the total production lot. In addition, see Para. 4.6.2 for distribution of the sample.

FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS

Not applicable.

TABLE 4 - PARAMETER DRIFT VALUES

No.	Characteristics	Symbol	Spec. and/or Test Method	Test Conditions	Change Limits (Δ)	Unit
1	Resistance Change	<u>ΔR</u> A RA	As per Table 2	As per Table 2	±0.5 or (1) ±0.05	% - Ω

NOTES

1. Whichever is greater.



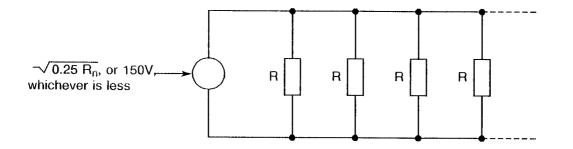
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TABLE 5 - CONDITIONS FOR BURN-IN AND OPERATING LIFE TESTS

No.	Characteristics	Symbol	Condition	Unit
1	Ambient Temperature	T _{amb}	+ 70 ± 3	°C
2	Test Voltage	V _T	√ 0.25 R _n , or 150V, whichever is less	V

. . _

FIGURE 5 - ELECTRICAL CIRCUIT FOR BURN-IN AND OPERATING LIFE TESTS





4.8 <u>ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC</u> <u>SPECIFICATION No. 4001</u>)

The resistors shall be mounted as prescribed in ESA/SCC Generic Specification No. 4001, Para. 9.20. The substrate material shall be epoxy glass laminated pointing board.

4.8.1 <u>Measurements and Inspections on Completion of Environmental Tests</u>

The parameters to be measured and inspections to be performed on completion of environmental tests are scheduled in Table 6. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.2 Measurements and Inspections at Intermediate Points during Endurance Tests

The parameters to be measured and inspections to be performed at intermediate points during endurance tests are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at T_{amb} = +22 ± 3 °C.

4.8.3 Measurements and Inspections on Completion of Endurance Tests

The parameters to be measured and inspections to be performed on completion of endurance testing are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.4 <u>Conditions for Operating Life Tests (Part of Endurance Testing)</u>

The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 4001. The conditions for operating life testing shall be as specified in Table 5 of this specification.

4.8.5 <u>Electrical Circuits for Operating Life Tests</u>

Circuits for use in performing the operating life tests are shown in Figure 5 of this specification.

4.8.6 <u>Conditions for High Temperature Storage Test (Part of Endurance Testing)</u>

The requirements for the high temperature storage test are specified in ESA/SCC Generic Specification No. 4001. The conditions for high temperature storage shall be T_{amb} = +155(+0-5) °C.



TABLE 6 - MEASUREMENTS AND INSPECTIONS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING

	ESA/SCC GENERIC	SPEC. NO. 4001	MEASUREMENTS A	ND INSPECTIONS		LIN	IITS	1
NO.	ENVIRONMENTAL AND ENDURANCE TESTS (1)	TEST METHOD AND CONDITIONS	IDENTIFICATION	CONDITIONS	SYMBOL	MIN.	MAX.	UNIT
01	Overload	Para. 9.1 and Paras 4.2.2 and 4.2.4 of this spec.	Initial Measurements Chart IV Resistance Final Measurements Visual Examination Chart II Resistance Chart IV Resistance Change	Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage and marking legible Table 2 Item 1 Table 2 Item 1	R _A R _A ΔR _A /R _A	Table 2	Values 2 Item 1 <u>05Ω × 100</u>) Βn	- %
02	Seal Test (Hermetically Sealed only)	Para. 9.3	Not applicable					
03	Insulation Resistance (Insulated only)	Para. 9.6	Final Measurements Insulation Resistance	Para. 9.6.2 of ESA/SCC 4001 (2)	Ri	1000	-	MΩ
04	Temperature Coefficient	Para. 9.7 Procedure I	Temperature Coefficient	Para. 9.5.1 of ESA/SCC 4001	TC	- 100 - 200	+ 100 + 200	10 ^{−6/} °C
05	Voltage Proof	Para. 9.8	During Test Visual Examination	1.4 × U _i (3) for 60 ± 5 sec No breakdown or flashover	-	-	-	-
06	Solderability	Para. 9.9 and Paras 4.2.4 and 4.2.5 of this spec. Procedure I	Initial Measurements Resistance Final Measurements Resistance Change	After Drying Table 2 Item 1 24 ± 4 hrs after soldering Table 2 Item 1	R_A $\Delta R_A/R_A$	Record ± (0.25 + <u>0.</u>	Values 05Ω × 100)	%
07	Robustness of Terminations	Para. 9.10.2 and Paras 4.2.4 and 4.2.5 of this spec. Adhesion Bend Strength of End Plate Facing	Initial Measurements Resistance Final Measurements Resistance Change Visual Examination Initial Measurements Resistance Final Measurements Resistance Change Visual Examination	After Mounting Table 2 Item 1 Table 2 Item 1 No damage, lifting, cracking or dry joints Table 2 Item 1 Board in bent position Table 2 Item 1 No damage, lifting, cracking or dry joints	R_A $\Delta R_A/R_A$ R_A $\Delta R_A/R_A$ $-$	- Record ± (0.25 + <u>0.</u> Record ± (0.25 + <u>0.</u>	05Ω × 100) Rn Values	- % - %
	Resistance to Soldering Heat	Para. 9.11 and Paras 4.2.4 and 4.2.5 of this spec. Procedure I	Initial Measurements Resistance Final Measurements Visual Examination Resistance Change	After Drying Table 2 Item 1 No evidence of damage and marking legible After 24 ± 4 hours Table 2 Item 1	R _A - ΔR _A /R _A	Record - ± (0.5 + <u>0.0</u>	~	Ω - %

<u>NOTES</u>

- 1. The tests in this Table refer to either Chart IV or V and shall be used as applicable.
 - 2. Test Voltage: $V_T = 100V$.
 - 3. For value of U_i , see Table 1(b) Item 4.



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TABLE 6 - MEASUREMENTS AND INSPECTIONS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING (CONT'D)

	ESA/SCC GENERIC	SPEC. NO. 4001	MEASUREMENTS A	ND INSPECTIONS		LIM	IITS	
NO.	ENVIRONMENTAL AND ENDURANCE TESTS (1)	TEST METHOD AND CONDITIONS	IDENTIFICATION	CONDITIONS	SYMBOL	MIN.	MAX.	UNIT
09	Rapid Change of Temperature	Para. 9.12	Initial Measurements Resistance Final Measurements Visual Examination Resistance Change	Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage Table 2 Item 1	R_A - $\Delta R_A/R_A$	-	Values - 05 <u>Ω × 100</u>) Bn	- . %
10	Vibration	Para. 9.13 and Paras 4.2.4 and 4.2.5 of this spec.	Not applicable					
11	Climatic Sequence	Para. 9.14 Procedure I	Initial Measurements Resistance Final Measurements Visual Examination	After Drying Table 2 Item 1 Following completion of D.C. load lest and after a recovery period of 1-2 hrs No evidence of damage and marking	R _A	Record	Values	-
			Insulation Resistance	legible Para. 9.6 of ESA/SCC 4001 (2)	Ri	1000	-	MΩ
			Resistance Change	Table 2 Item 1	$\Delta R_A/R_A$	± (1.0 + <u>0.0</u>	<u>05Ω×100</u>) Rn	%
12	Operating Life	Para. 9.15 Chart IV	Initial Measurements Resistance Intermediate Measurements (1000 hrs)	Table 2 Item 1 After a recovery period of 1-2 hrs	R _A	Record	Values	
			Visual Examination Resistance Change	No evidence of damage Table 2 Item 1	ΔR _A /R _A	- ± (1.0 + <u>0.(</u>		- %
			Final Measurements (2000 hrs) Visual Examination Resistance Change	After a recovery period of 1-2 hrs No evidence of damage Table 2 Item 1	- ΔR _A /R _A	- ± (1.5 + <u>0.0</u>	Rn - 5Ω × 100)	- %
			Insulation Resistance	Para. 9.6 of ESA/SCC 4001 (2)	Ri	1000	Rn	MΩ
		Para. 9.15 Chart V	Initial Measurements Resistance Final Measurements (1000 hrs) Visual Examination	Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage	R _A	Record	Values -	_
			Resistance Change	Table 2 Item 1	$\Delta R_A/R_A$	± (1.0 + <u>0.0</u>	<u>5Ω×100</u>) Rn	%
			Insulation Resistance	Para. 9.6 of ESA/SCC 4001 (2)	Ri	1000	-	MΩ

NOTES: See Page 16.



TABLE 6 - MEASUREMENTS AND INSPECTIONS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING (CONT'D)

	ESA/SCC GENERIC SPEC. NO. 4001		MEASUREMENTS A		LIM	ITS		
NO.	ENVIRONMENTAL AND ENDURANCE TESTS (1)	TEST METHOD AND CONDITIONS	IDENTIFICATION	CONDITIONS	SYMBOL	MIN.	MAX.	UNIT
13	High Temperature Storage	Para. 9.16	Initial Measurements Resistance Intermediate Measurements (1000 hrs)	Table 2 Item 1 After a recovery period of 1-2 hrs	R _A	Record	Values	
			Visual Examination Resistance Change	No evidence of damage Table 2 Item 1	- ΔR _A /R _A	- <u>+</u> (1.0 + <u>0.0</u>		~ %
			Final Measurements (2000 hrs) Visual Examination	After a recovery period of 1-2 hrs No evidence of damage	-	-	Rn -	-
			Resistance Change	Table 2 Item 1	$\Delta R_A/R_A$	<u>+</u> (1.5 + <u>0.(</u>	<u>)5Ω×100</u>) Rn	[.] %
			Insulation Resistance	Para. 9.6 of ESA/SCC 4001 (2)	Ri	1000	-	MΩ
14	Permanence of Marking	Para. 9.19	*	-	-	-	-	-

NOTES: See Page 16.